

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 1 of 10

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,809,361 A	02-1989	Okada et al.	398/36
*	B	US-4,845,703 A	07-1989	Suzuki, Syuji	398/48
*	C	US-4,994,675 A	02-1991	Levin et al.	250/551
*	D	US-5,130,984 A	07-1992	Cisneros, Arturo	370/399
*	E	US-5,144,297 A	09-1992	Ohara, Katsuichi	340/2.26
*	F	US-5,157,654 A	10-1992	Cisneros, Arturo	370/414
*	G	US-5,166,926 A	11-1992	Cisneros et al.	370/392
*	H	US-5,296,850 A	03-1994	King, Fred N.	340/825.49
*	I	US-5,319,482 A	06-1994	Tsuchiya et al.	398/31
*	J	US-5,452,115 A	09-1995	Tomioka, Tazuko	398/75
*	K	US-5,488,501 A	01-1996	Barnsley, Peter E.	398/51
*	L	US-5,495,358 A	02-1996	Bartig et al.	398/202
*	M	US-5,521,732 A	05-1996	Nishio, Makoto	398/51

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 2 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,537,393 A	07-1996	Shioda et al.	370/223
*	B US-5,539,564 A	07-1996	Kumozaki et al.	398/2
*	C US-5,559,624 A	09-1996	Darcie et al.	398/72
*	D US-5,627,925 A	05-1997	Alferness et al.	385/17
*	E US-5,679,987 A	10-1997	Ogawa, Hideharu	307/147
*	F US-5,682,257 A	10-1997	Uchida, Tetsuya	398/43
*	G US-5,708,753 A	01-1998	Frigo et al.	385/147
*	H US-5,777,761 A	07-1998	Fee, John A.	398/7
*	I US-5,844,702 A	12-1998	Yarkosky et al.	398/139
*	J US-5,867,289 A	02-1999	Gerstel et al.	398/12
*	K US-5,896,212 A	04-1999	Sotom et al.	398/55
*	L US-5,920,414 A	07-1999	Miyachi et al.	398/14
*	M US-5,970,201 A	10-1999	Anthony et al.	385/140

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 3 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,978,113 A	11-1999	Kight, William Dorsey	398/1
*	B US-6,101,014 A	08-2000	Majima, Masao	398/69
*	C US-6,137,927 A	10-2000	Keck et al.	385/24
*	D US-6,229,788 B1	05-2001	Graves et al.	370/230
*	E US-6,246,511 B1	06-2001	Jameson, Ralph S.	359/337
*	F US-6,332,055 B1	12-2001	Hatayama et al.	385/140
*	G US-2002/0015200	02-2002	JENNINGS et al.	359/124
*	H US-2002/0015209 A1	02-2002	Suzuki, Yukihiko	359/173
*	I US-2002/0018265 A1	02-2002	Graves, Alan F.	359/128
*	J US-2002/0027689 A1	03-2002	Bartur et al.	359/152
*	K US-2002/0041409 A1	04-2002	Laham et al.	359/110
*	L US-2002/0044315 A1	04-2002	Sugawara et al.	359/110
*	M US-6,369,926 B1	04-2002	Lyu et al.	398/95

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 4 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2002/0080438 A1	06-2002	Beine et al.	359/110
*	B US-2002/0097682 A1	07-2002	Enam et al.	370/241
*	C US-6,417,944 B1	07-2002	Lahat et al.	398/79
*	D US-2002/0109882 A1	08-2002	Araki et al.	359/139
*	E US-2002/0109879 A1	08-2002	Wing So, John Ling	359/118
*	F US-6,433,900 B1	08-2002	Kuroyanagi et al.	398/19
*	G US-2002/0126342 A1	09-2002	Wetzel et al.	359/117
*	H US-2002/0131120 A1	09-2002	Araki et al.	359/139
*	I US-6,466,343 B1	10-2002	Lahat et al.	398/82
*	J US-2002/0163683 A1	11-2002	Antoniades et al.	359/110
*	K US-6,504,969 B1	01-2003	Tsao et al.	385/24
*	L US-6,507,421 B1	01-2003	Bishop et al.	398/56
*	M US-6,574,018 B1	06-2003	Handelman, Doron	398/49

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 5 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,580,531 B1	06-2003	Swanson et al.	398/5
*	B US-6,583,901 B1	06-2003	Hung, Henry	398/79
*	C US-6,590,681 B1	07-2003	Egnell et al.	398/82
*	D US-2003/0152390 A1	08-2003	Stewart et al.	398/135
*	E US- H,002,075 H	08-2003	Gnauck et al.	398/58
*	F US-2003/0174659 A1	09-2003	Handelman, Doron	370/280
*	G US-6,671,469 B1	12-2003	Fukagawa et al.	399/30
*	H US-2004/0008989 A1	01-2004	Hung, Henry	398/69
*	I US-2004/0017967 A1	01-2004	Tajima, Akio	385/24
*	J US-6,704,508 B1	03-2004	Asahi, Koji	398/30
*	K US-2004/0052524 A1	03-2004	Arnold, Philip	398/038
*	L US-2004/0042796 A1	03-2004	Con-Carolis et al.	398/083
*	M US-6,721,502 B1	04-2004	Al-Salameh et al.	398/3

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 6 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,738,581 B2	05-2004	Handelman, Doron	398/79
*	B US-2004/0190905 A1	09-2004	Kano, Shinya	398/141
*	C US-6,798,991 B1	09-2004	Davis et al.	398/19
*	D US-6,810,214 B2	10-2004	Chbat et al.	398/160
*	E US-2004/0208574 A1	10-2004	Kinoshita et al.	398/083
*	F US-2004/0208510 A1	10-2004	Ohara, Katsuichi	398/019
*	G US-6,804,463 B1	10-2004	Arecco et al.	398/19
*	H US-6,801,679 B2	10-2004	Koh et al.	385/14
*	I US-6,826,368 B1	11-2004	Koren et al.	398/50
*	J US-6,868,232 B2	03-2005	Eijk et al.	398/5
*	K US-6,871,021 B2	03-2005	Graves et al.	398/45
*	L US-2005/0074236 A1	04-2005	Urimindi et al.	398/012
*	M US-6,920,287 B1	07-2005	Hinds et al.	398/9

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 7 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0163503 A1	07-2005	Lee et al.	398/019
*	B US-6,934,472 B2	08-2005	Chang et al.	398/51
*	C US-2005/0196165 A1	09-2005	Dybsetter et al.	398/022
*	D US-6,957,018 B2	10-2005	Araki et al.	398/51
*	E US-6,965,735 B2	11-2005	Wu et al.	398/12
*	F US-6,973,228 B2	12-2005	Chang et al.	385/14
*	G US-6,973,269 B1	12-2005	Britz et al.	398/51
*	H US-6,980,711 B2	12-2005	Feinberg et al.	385/16
*	I US-6,983,109 B1	01-2006	Britz et al.	398/51
*	J US-2006/0013585 A1	01-2006	Hnatiw et al.	398/038
*	K US-2006/0013584 A1	01-2006	Miyazaki, Keiji	398/019
*	L US-6,999,677 B2	02-2006	Graves et al.	398/5
*	M US-2006/0045520 A1	03-2006	Nakano et al.	398/033

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 8 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2006/0056843 A1	03-2006	Fee et al.	398/019
*	B US-7,035,537 B2	04-2006	Wang et al.	398/7
*	C US-7,039,316 B2	05-2006	Chang et al.	398/51
*	D US-7,039,318 B2	05-2006	Graves, Alan F.	398/81
*	E US-7,046,928 B1	05-2006	Bradford et al.	398/9
*	F US-7,065,268 B2	06-2006	Prairie et al.	385/17
*	G US-7,079,715 B2	07-2006	Kish et al.	385/14
*	H US-7,076,163 B2	07-2006	Kinoshita et al.	398/19
*	I US-7,099,578 B1	08-2006	Gerstel, Ornan A.	398/5
*	J US-2006/0269282 A1	11-2006	Gerstel, Ornan A.	398/019
*	K US-7,146,103 B2	12-2006	Yee et al.	398/68
*	L US-7,151,893 B2	12-2006	Hayashi et al.	398/7
*	M US-7,155,127 B2	12-2006	Akimoto et al.	398/72

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 9 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,174,066 B1	02-2007	Look, Christopher M.	385/17
*	B US-7,212,739 B2	05-2007	Graves et al.	398/5
*	C US-2007/0147835 A1	06-2007	Kim et al.	398/71
*	D US-7,239,773 B2	07-2007	Sakai et al.	385/18
*	E US-7,242,861 B2	07-2007	Sato et al.	398/19
*	F US-7,266,297 B2	09-2007	Schafer et al.	398/56
*	G US-2007/0230954 A1	10-2007	SAKAI et al.	398/012
*	H US-2007/0237521 A1	10-2007	Meyer et al.	398/019
*	I US-7,317,875 B2	01-2008	Moriwaki et al.	398/87
*	J US-2008/0050117 A1	02-2008	Koley, Bikash	398/049
*	K US-7,326,916 B2	02-2008	Sugiyama et al.	250/227.14
*	L US-7,376,348 B2	05-2008	Hasuo et al.	398/5
*	M US-7,398,018 B2	07-2008	Ohara, Katsuichi	398/5

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N				
*	O				
*	P				
*	Q				
*	R				
*	S				
*	T				

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U
*	V
*	W
*	X

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/785,617

Applicant(s)/Patent Under
Reexamination

LOOK, CHRISTOPHER M.

Examiner

DANNY W. LEUNG

Art Unit

2613

Page 10 of 10

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-7,426,347 B2	09-2008	Hnatiw et al.	398/38
*	B US-7,474,851 B2	01-2009	Inman et al.	398/22
*	C US-2009/0034965 A1	02-2009	Look, Christopher M.	398/19
*	D US-2009/0080881 A1	03-2009	Yokoyama, Yoshitaka	398/16
*	E US-7,526,200 B2	04-2009	Nakano et al.	398/34
*	F US-7,533,254 B2	05-2009	Dybsetter et al.	713/2
*	G US-5,502,587 A	03-1996	Frigo, Nicholas J.	398/58
*	H US-2005/0108444 A1	05-2005	Flauaus et al.	710/015
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.